


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/697,755	NOBUSAWA ET AL.	
	Examiner	Art Unit	
	James D. Ewart	2617	

SEARCHED			
Class	Subclass	Date	Examiner
455	68	5/17/2006	JDE
	186.1		
	186.2		
	352		
	418-420		
	425		
	550.1		
	552.1		
	556.1		
379	93.17		
	110.01		
345	168		
	169		
348	14.01		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR

**Search Notes (continued)**



**Application/Control No.**

10/697,755

**Examiner**

James D. Ewart

**Applicant(s)/Patent under  
Reexamination**

NOBUSAWA ET AL.

**Art Unit**

2617

**SEARCHED**

Class	Subclass	Date	Examiner
348	14.02	5/17/2006	JDE
	14.04		
	14.05		
	552		
	553		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR